

# Sriram S R

## List of Publications by Year in descending order

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9  
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1937685

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#	ARTICLE	IF	CITATIONS
1	A physics-based model for LER-induced threshold voltage variations in double-gate MOSFET. Journal of Computational Electronics, 2020, 19, 622-630.	2.5	5
2	An Analytical Model of Single-Event Transients in Double-Gate MOSFET for Circuit Simulation. IEEE Transactions on Electron Devices, 2019, 66, 3710-3717.	3.0	14
3	Analytical Model for RDF-Induced Threshold Voltage Fluctuations in Double-Gate MOSFET. IEEE Transactions on Device and Materials Reliability, 2019, 19, 370-377.	2.0	3
4	A physics-based 3-D potential and threshold voltage model for undoped triple-gate FinFET with interface trapped charges. Journal of Computational Electronics, 2019, 18, 37-45.	2.5	8
5	Analytical model of hot carrier degradation in uniaxial strained triple-gate FinFET for circuit simulation. Journal of Computational Electronics, 2018, 17, 163-171.	2.5	7
6	Hot Carrier Reliability in 45 nm Strained Si/relaxed Si <sub>x</sub> Ge <sub>1-x</sub> CMOS Based SRAM Cell. , 2018, , .		1
7	Impact of NBTI induced variations on FinFET based Vernier delay line time to digital converter. , 2017, , .		0
8	Impact of NBTI induced variations on delay locked loop multi-phase clock generator. Microelectronics Reliability, 2016, 60, 33-40.	1.7	8
9	Design of FinFET based frequency synthesizer. , 2015, , .		0